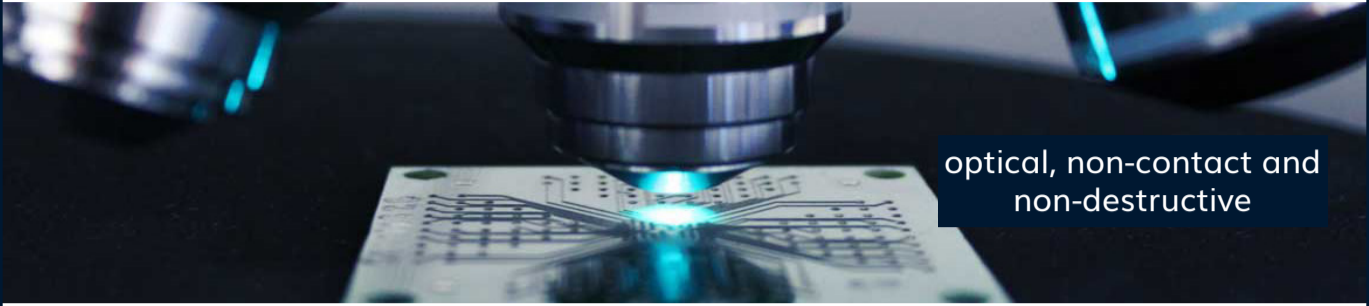


3D surface measurement with sub-micrometer lateral resolution

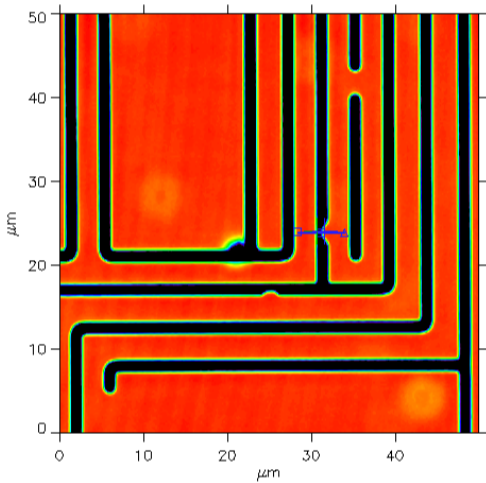


optical, non-contact and non-destructive

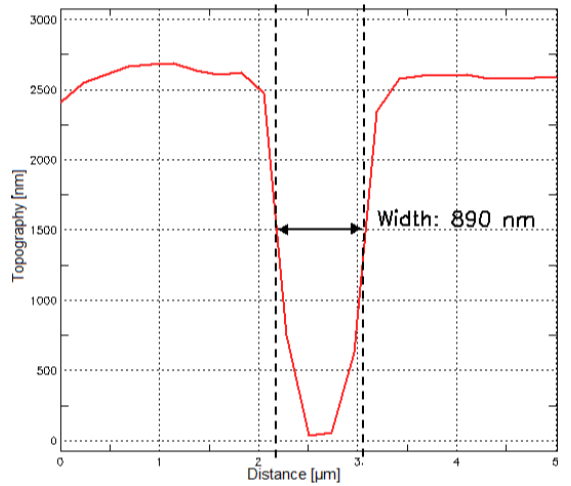
Know-how of confocal microscopy

- > 3D topography, roughness, geometry, contour, diameter, defect inspection, step height and width ...
- > nanometer vertical resolution, sub-micrometer lateral resolution
- > very fast area measurement
- > extendible field of view through stitching
- > durable, low-maintenance LED light source
- > integrable in a multi-sensor system

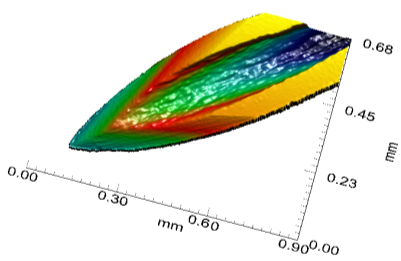
and much more...



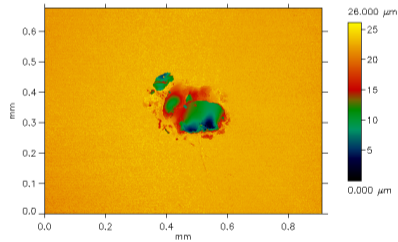
Area measurement of a wafer with trenches, CFM 100x



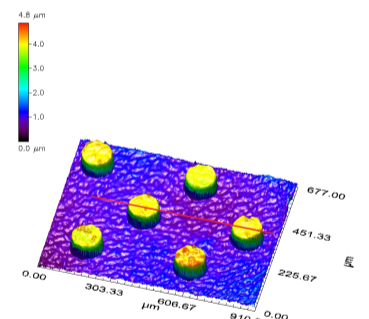
Profile measurement of a small single trench



Topography of an injection needle



Topography measurement of a defect on a lens



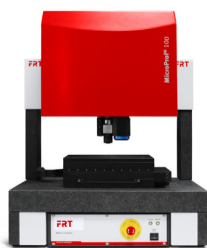
Sapphire wafer with gold microstructure

Technical solution



CFM - field-of-view sensor for confocal microscopy

Use the sensor in our MicroProf® tools, for example in



MicroProf® 100



MicroProf® FS